Am2814/3114

Dual 128-Bit Static Shift Register

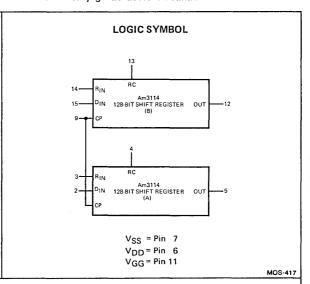
Distinctive Characteristics

- 2nd Source to Texas Instruments 3114
- Operation guaranteed from DC to 2.5MHz.
- 100% reliability assurance testing in compliance with MIL-STD-883
- Full military grade devices available

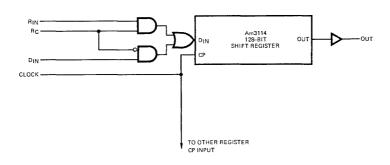
FUNCTIONAL DESCRIPTION

The Am3114 is a dual 128-bit static shift register built using P-channel silicon gate MOS technology. The two registers each have a two-input multiplexer on their inputs, so that input data may be selected from one of two sources. Both registers have a common clock input, and operate with a low-voltage TTL clock signal. The registers shift on the LOW-to-HIGH edge of the clock signal. Data at the inputs must be steady for a set-up time before and a hold time after this clock transition. Since data storage is static, the clock may be halted indefinitely in the HIGH state. The outputs of each register can drive one TTL load or three Am93L low-power TTL loads.

The two-input multiplexer on the input of each register is controlled by the RC (recirculate control) input. When RC is LOW, data is accepted on the D_{in} input; when RC is HIGH, data is accepted on the R_{in} input. The Am2814 is functionally identical to the Am3114, but is specified with higher performance.



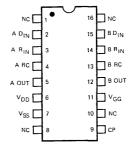




ORDERING INFORMATION

Package Type	Temperature Range	Am3114 Order Number	Am2814 Order Number
Molded DIP Hermetic DIP Hermetic DIP	-25° C to +85° C -25° C to +85° C -55° C to +125° C	TMS3114NC TMS3114JC	AM2814PC AM2814DC AM2814DM

CONNECTION DIAGRAM



Notes: 1. Pin 1 is marked for orientation.
2. NC = No Connection.

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MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
V _{DD} Supply Voltage	V _{SS} -10V to V _{SS} +0.3V
V _{GG} Supply Voltage	V _{SS} -20V to V _{SS} +0.3V
DC Input Voltage	V _{SS} -15V to V _{SS} +0.3V

OPERATING RANGE

Part Number	T_A	VSS	v_{GG}	v_{DD}
Am2814PC, DC Am3114JC, NC	-25°C to +85°C	5.0V ±5%	-11V to -13V	GND
Am2814DM	-55°C to +125°C	5.0V ±5%	-11.4V to -12.6V	GND

ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless otherwise noted)

arameters	Description	Test Conditions		Min.	Typ. (Note 1)	Max.	Units	
v _{OH}	Output HIGH Voltage	I _{OH} = −200μA			V _{SS} -1			Volts
v _{OH}	Output LOW Voltage	I _{OL} = 1.6mA				0.2	0.4	Volts
VIH	Input HIGH Level	Guaranteed input logical HIGH Am3114		3.5			Volts	
	1	voltage for all inputs Guaranteed input logical LO	W	Am2814	V _{SS} -1.5		0.0	27-14-
V _{IL}	Input LOW Level	voltage for all inputs				0.6	Volts	
կլ	Input LOW Current	V _{SS} = MAX., V _{IN} = 0.6V				0.5	μΑ	
ЧН	Input HIGH Current	VIN = VSS	VIN = VSS				0.5	μΑ
			Am	3114		15		
I _{SS} V _{SS}	V _{SS} Power Supply Current	Inputs and Outputs Open f = 1MHz	Am2814XC			14	25	
		Am2814XI		2814XM		14	35	mA
I _{GG}	VGG Power Supply Current	Am3114 Inputs and Outputs Open		3114		4		11171
				2814XC		-4	-10	
				2814XM		-4	-15	

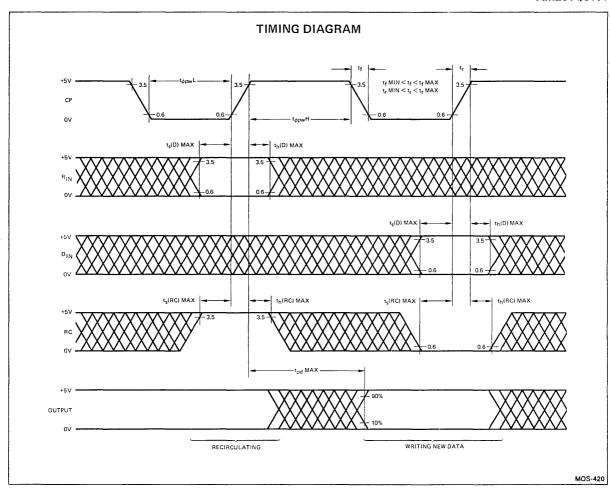
Note 1. Typical Limits are at $V_{SS} = 5.0 \, \text{V}$, $V_{GG} = -12 \, \text{V}$, 25°C ambient and maximum loading.

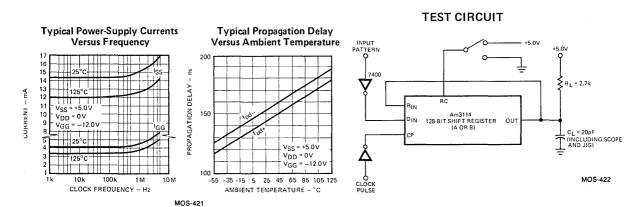
SWITCHING CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)

				Am3114		Am2814			
arameters	Description	Test Conditions	Min.	Тур.	Max.	Min.	Тур.	Max.	Units
f _{max}	Maximum Clock Frequency		2.0			2.5			MHz
$t_{\phi pw}H$	Clock HIGH Time		.330		- 00	.200			μs
t _{opw} L	Clock LOW Time		.130		100	.170		100	μs
t _r , t _f	Clock Rise and Fall Times				5			5	μs
t _s (D)	Set-up Time, D or R Inputs (see definitions)		100			100			ns
t _h (D)	Hold Time, D or R Inputs (see definitions)	$t_r = t_f \le 50$ ns	100			100			ns
t _s (RC)	Set-up Time, RC Input (see definitions)		100			100			ns
th(RC)	Hold Time, RC Input (see definitions)		150			150			ns
t _{pd}	Delay, Clock to Output LOW or HIGH	R _L = 2.7k, C _L = 20pF			350	(Note 4)		250	ns
t _{pr} , t _{pF}	Output Rise and Fall Times	10% to 90%						100	ns
Cin	Capacitance, Any Input (Note 3)	f = 1 MHz, VIN = VSS			13		3	7	pF

Notes: 3. This parameter is periodically sampled but not 100% tested. It is guaranteed by design.

^{4.} At any temperature, t_{pd} min. is always much greater than $t_h(D)$ max.



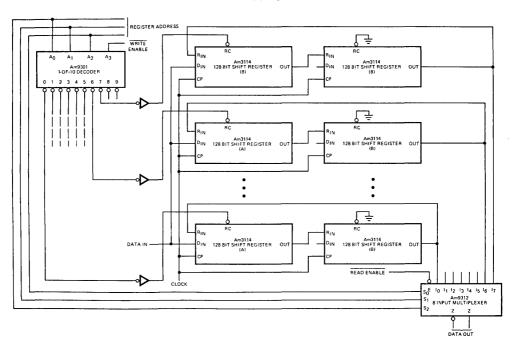


DEFINITION OF TERMS

TATIC SHIFT REGISTER A shift register that is capable of naintaining stored data without being continuously clocked. Asst static, shift registers are constructed with dynamic master nd static slave flip-flops. The data is stored dynamically while he clock is LOW and is transferred to the static slaves while the lock is HIGH. The clock may be stopped indefinitely in the IIGH state, but there are limitations on the time it may reside the LOW state.

SET-UP and HOLD TIMES The shift register will accept the data that is present on its input around the time the clock goes from LOW-to-HIGH. Because of variations in individual devices, there is some uncertainty as to exactly when, relative to this clock transition, the data will be stored. The set-up and hold times define the limits on this uncertainty. To guarantee storing the correct data, the data inputs should not be changed between the maximum set-up time before the clock transition and the maximum hold time after the clock transition. Data changes within this interval may or may not be detected.

APPLICATIONS



Eight Register 256-Bit Memory System

Data enters one of the eight 256-bit registers when the write enable input to the decoder is LOW. The addressed register will accept the data on the data input; the other seven registers will recirculate their data. Outputs are driven directly into an Am9312 8-input multiplexer. Obviously, the read and write registers need not be the same. Pull-up resistors are required on all register inputs driven from TTL.

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TRUTH TABLE

RC	D _{IN}	RIN	Data Entered
L	L	×	L
L	н	×	Н
н	X	L	L
н	×	Н	н

H = HIGH Voltage level L = LOW Voltage Level

X = Don't Care